



TEST REPORT

REGULATION : **FCC Part 1.1310**
(General Population/Uncontrolled Exposure)

Applicant	Testing Laboratory
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Equipment type Trademark FCC Model(s) IC Model(s) Serial No. FCC ID IC CN and UPN Test Result Report Number Report issue date	VHF DIGITAL TRANSCEIVER KENWOOD NX-5700-K、NX-5700-F NX-5700-K 27 K44471100 282F-471100 Complied 14100002JKA-003 November 14, 2014

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Approved by

Kazuo Gokita

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Tested by

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[Engineer]

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SECTION 1. INFORMATION**APPLICANT**

Company	JVC KENWOOD Corporation
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Contact Person	Tamaki Shimamura

MANUFACTURER

Company	JVC KENWOOD Corporation
Address	1-16-2, Hakusan, Midori-ku, Yokohama-shi Kanagawa, 226-8525 Japan

EQUIPMENT UNDER TEST

FCC Model(s)	NX-5700-K, NX-5700-F		
IC Model(s)	NX-5700-K		
Serial No.	27		
Frequency range	FCC: 150 to 174 MHz , IC: 138 to 144 MHz and 148 to 174 MHz		
FCC ID	K44471100		
IC CN and UPN	282F-471100		
Maximum Power Rating	50	W	
Duty cycle	50	%	
Collector Current, A	13.0	amps (Maximum)	
Collector Voltage, Vdc	13.6	Vdc	
Supply Voltage, Vdc	13.6	Vdc	

TEST DATE OF ISSUE AND TEST ENGINEER

Date of Issue	October 14, 2014		
temperature	21	to	23.5 [degree C]
Humidity Variation	58	to	60 [%]
Atmospheric Pressure	100.7	to	100.7 [kPa]
Test Engineer	Koichi Wagatsuma		
Test Location	Kashima Immunity Test Room		
Regulations	FCC Part 1.1310 , RSS-102 Issue4 2010		
Test method/Guide	KDB 447498 D01 General RF Exposure Guidance v05r02		
Test Procedure	RJP-TE103		

Revision Summary

Revised Date	Section	Description of Changes

SECTION 2. TEST DATA

The TX antenna place was inside a semi anechoic chamber at height of 0.8 m from the Ground reference plane to simulate being mounted on a vehicle.

The isotropic probe position was a distance of 0.6 m from the TX antenna and the power density was measured from 0.1 m to 2.0 m (at 0.1 m increments) with the peak value.

The EUT is a PTT radio for mobile application with a peak output power of 50 W.

The 1/4 wave antenna (0 dBd gain) was utilized for testing.

(Model No : QWFT120 / Manufacturer : Laird Technologies)

Measurement Result

TX frequency (MHz)	Output Power W	Measurement distance (m)	Power Density (mW/cm ²)	Limit (mW/cm ²)	Result
138.05	50	0.6	0.121	0.200	PASS
150.05	50	0.6	0.107	0.200	PASS
158.05	50	0.6	0.051	0.200	PASS
162.05	50	0.6	0.043	0.200	PASS
173.95	50	0.6	0.068	0.200	PASS

Power Density = 20 measurements data (0.1m - 2.0m) has been averaged.

Limit : General Population/Uncontrolled Exposure

Measurement data

138.05 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.039	1.33	0.026
0.2	0.072	1.33	0.048
0.3	0.102	1.33	0.068
0.4	0.148	1.33	0.098
0.5	0.189	1.33	0.126
0.6	0.236	1.33	0.157
0.7	0.271	1.33	0.180
0.8	0.273	1.33	0.181
0.9	0.239	1.33	0.158
1.0	0.196	1.33	0.130
1.1	0.191	1.33	0.127
1.2	0.214	1.33	0.142
1.3	0.241	1.33	0.160
1.4	0.259	1.33	0.172
1.5	0.243	1.33	0.161
1.6	0.210	1.33	0.139
1.7	0.180	1.33	0.119
1.8	0.140	1.33	0.093
1.9	0.110	1.33	0.073
2.0	0.088	1.33	0.058

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

150.05 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.012	1.36	0.008
0.2	0.038	1.36	0.026
0.3	0.066	1.36	0.045
0.4	0.103	1.36	0.070
0.5	0.141	1.36	0.096
0.6	0.170	1.36	0.115
0.7	0.201	1.36	0.137
0.8	0.216	1.36	0.146
0.9	0.208	1.36	0.141
1.0	0.198	1.36	0.134
1.1	0.202	1.36	0.137
1.2	0.224	1.36	0.152
1.3	0.242	1.36	0.164
1.4	0.243	1.36	0.165
1.5	0.227	1.36	0.154
1.6	0.195	1.36	0.132
1.7	0.163	1.36	0.111
1.8	0.128	1.36	0.087
1.9	0.102	1.36	0.069
2.0	0.087	1.36	0.059

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

158.05 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.005	1.38	0.003
0.2	0.020	1.38	0.013
0.3	0.037	1.38	0.026
0.4	0.057	1.38	0.039
0.5	0.070	1.38	0.048
0.6	0.084	1.38	0.058
0.7	0.097	1.38	0.067
0.8	0.108	1.38	0.074
0.9	0.108	1.38	0.074
1.0	0.106	1.38	0.073
1.1	0.106	1.38	0.073
1.2	0.111	1.38	0.076
1.3	0.114	1.38	0.078
1.4	0.107	1.38	0.074
1.5	0.094	1.38	0.064
1.6	0.080	1.38	0.055
1.7	0.064	1.38	0.044
1.8	0.049	1.38	0.034
1.9	0.037	1.38	0.025
2.0	0.028	1.38	0.019

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

162.05 MHz

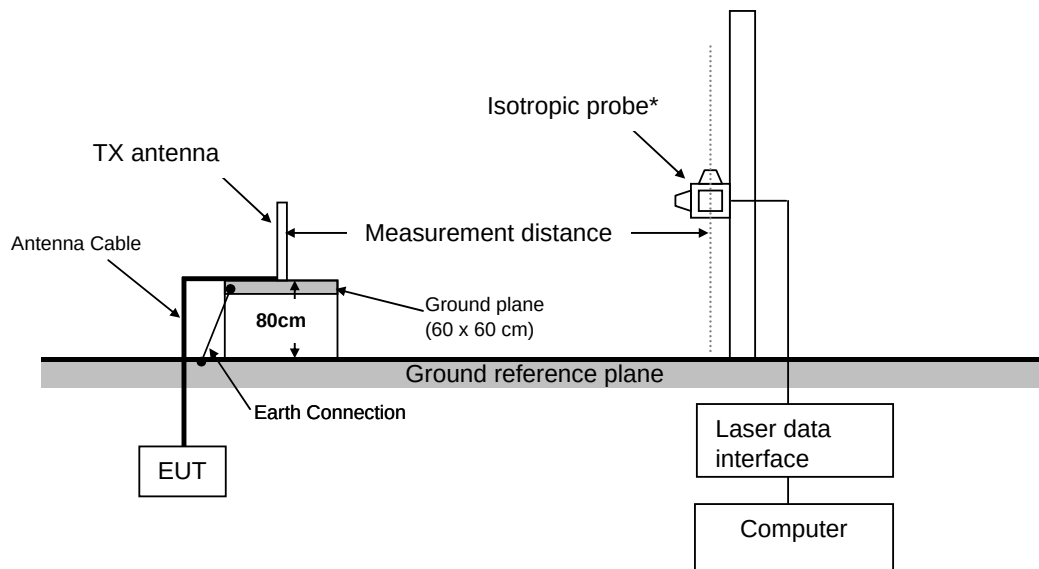
Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.004	1.39	0.003
0.2	0.016	1.39	0.011
0.3	0.030	1.39	0.021
0.4	0.046	1.39	0.032
0.5	0.057	1.39	0.040
0.6	0.067	1.39	0.046
0.7	0.080	1.39	0.055
0.8	0.090	1.39	0.062
0.9	0.089	1.39	0.061
1.0	0.090	1.39	0.062
1.1	0.092	1.39	0.064
1.2	0.094	1.39	0.065
1.3	0.096	1.39	0.066
1.4	0.091	1.39	0.063
1.5	0.083	1.39	0.058
1.6	0.070	1.39	0.048
1.7	0.056	1.39	0.039
1.8	0.043	1.39	0.030
1.9	0.032	1.39	0.022
2.0	0.024	1.39	0.017

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

173.95 MHz

Probe Height (m)	Reading Power Density (mW/cm ²)	Probe Factor	Power Density (mW/cm ²)
0.1	0.013	1.42	0.009
0.2	0.040	1.42	0.028
0.3	0.065	1.42	0.046
0.4	0.089	1.42	0.063
0.5	0.106	1.42	0.075
0.6	0.119	1.42	0.084
0.7	0.129	1.42	0.092
0.8	0.145	1.42	0.102
0.9	0.156	1.42	0.110
1.0	0.155	1.42	0.110
1.1	0.153	1.42	0.108
1.2	0.149	1.42	0.105
1.3	0.141	1.42	0.100
1.4	0.123	1.42	0.087
1.5	0.105	1.42	0.074
1.6	0.082	1.42	0.058
1.7	0.062	1.42	0.044
1.8	0.044	1.42	0.031
1.9	0.032	1.42	0.023
2.0	0.023	1.42	0.016

Power Density = Reading Power Density x Probe Factor x Duty cycle (50%)

SECTION 3. TEST CONFIGURATION

* : The Isotropic probe position was Vertical orientation from the Ground reference plane from 0.1m to 2m (10cm increments) .

Setup Photos

SECTION 4. MEASUREMENT UNCERTAINTY

30 MHz – 1000 MHz	17.7 % (k=2)
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SECTION 5. LIST OF MEASURING INSTRUMENTS

Instrument	Model No.	Serial No.	Manufacturer	Cal Date	Cal Due Date
Isotropic probe	HI-6105	00130667	ETS Lindgren	2014/4/2	2015/4/30
Laser data interface	HI 6113	00130903	ETS Lindgren	N/A	N/A
Testing software	ProbeView™ Laser	Version 2.0.8	ETS Lindgren	N/A	N/A